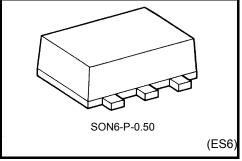
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7PH34FE

#### **Dual NON-Inverter**

#### Features

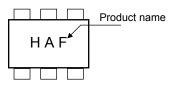
- Operating voltage range
- High-speed operation
- Low power dissipation
- High noise immunity
- 5.5-V tolerant inputs
- : V<sub>CC</sub> = 2.0~5.5 V
- : t<sub>pd</sub> = 3.8 ns (typ.)
  - at  $V_{CC} = 5 V, C_{L} = 15 pF$
- :I<sub>CC</sub> = 2 μA (max) at Ta=25°C
- $:V_{NIH} = V_{NIL} = 28 \% V_{CC}(min)$

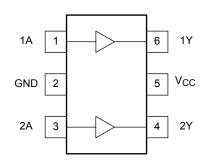


Weight: 0.003g (typ.)

### Marking

### Pin Assignment (top view)





### Absolute Maximum Ratings (Ta = 25°C)

| Characteristics                    | Symbol           | Rating                   | Unit |  |
|------------------------------------|------------------|--------------------------|------|--|
| Supply voltage range               | V <sub>CC</sub>  | -0.5~7.0                 | V    |  |
| DC input voltage                   | V <sub>IN</sub>  | -0.5~7.0                 | V    |  |
| DC output voltage                  | V <sub>OUT</sub> | $-0.5 \sim V_{CC} + 0.5$ | V    |  |
| Input diode current                | I <sub>IK</sub>  | -20                      | mA   |  |
| Output diode current               | IOK              | ±20                      | mA   |  |
| DC output current                  | IOUT             | ±25                      | mA   |  |
| DC V <sub>CC</sub> /ground current | ICC              | ±50                      | mA   |  |
| Power dissipation                  | PD               | 150                      | mW   |  |
| Storage temperature                | T <sub>stg</sub> | -65~150                  | °C   |  |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## <u>TOSHIBA</u>

### Logic Diagram



| А | Y |
|---|---|
| L | L |
| Н | Н |

### **Operating Ranges**

| Characteristics          | Symbol           | Rating                                   | Unit   |  |
|--------------------------|------------------|--|--------|--|
| Supply voltage           | V <sub>CC</sub>  | 2~5.5                                    | V      |  |
| Input voltage            | V <sub>IN</sub>  | 0~5.5                                    | V      |  |
| Output voltage           | V <sub>OUT</sub> | 0~ V <sub>CC</sub>                       | V      |  |
| Operating temperature    | T <sub>opr</sub> | -40~85                                   | °C     |  |
| Input rise and fall time | dt/dv            | 0~100 (V_{CC} = 3.3 V $\pm$ 0.3 V)       | ns/V   |  |
|                          | uvuv             | 0~20 (V <sub>CC</sub> = 5 V $\pm$ 0.5 V) | 113/ V |  |

### **Electrical Characteristics**

### **DC Characteristics**

| Characteristics Symbol                                      |                 | Tool                            | Test Condition           |                       | ٦    | Га = 25°0             | С                     | Ta = −40~85°C         |      | Unit |
|---|-----------------|---------------------------------|--------------------------|-----------------------|------|-----------------------|-----------------------|-----------------------|------|------|
|   |                 | Test                            |                          |                       | Min  | Тур.                  | Max                   | Min                   | Max  | Unit |
| High lovel input  |                 |                                 |                          |                       | 1.5  | _                     | _                     | 1.5                   |      |      |
| High-level input<br>voltage                                 |                 | —                               | 3.0~5.5                  | V <sub>CC</sub> × 0.7 |      | _                     | V <sub>CC</sub> × 0.7 | _                     | V    |      |
| Low-level input<br>voltage                                  |                 |                                 |                          | _                     |      | 0.50                  |                       | 0.50                  |      |      |
|   |                 | _                               | 3.0~5.5                  | _                     |      | V <sub>CC</sub> × 0.3 | _                     | V <sub>CC</sub> × 0.3 | V    |      |
|   |                 | VIN = VIH                       | I <sub>OH</sub> = -50 μA | 2.0                   | 1.9  | 2.0                   | _                     | 1.9                   |      | V    |
|   |                 |                                 |                          | 3.0                   | 2.9  | 3.0                   | _                     | 2.9                   |      |      |
| High-level Voltage Voltage                                  | V <sub>OH</sub> |                                 |                          | 4.5                   | 4.4  | 4.5                   | _                     | 4.4                   | _    |      |
|   |                 |                                 | $I_{OH} = -4 \text{ mA}$ | 3.0                   | 2.58 | _                     | _                     | 2.48                  | _    |      |
|   |                 |                                 | $I_{OH} = -8 \text{ mA}$ | 4.5                   | 3.94 | _                     | _                     | 3.80                  | _    |      |
| Low-level output V <sub>OL</sub> V <sub>IN</sub><br>voltage |                 |                                 | 2.0                      | _                     | 0.0  | 0.1                   |                       | 0.1                   |      |      |
|   |                 |                                 | I <sub>OL</sub> = 50 μA  | 3.0                   | —    | 0.0                   | 0.1                   |                       | 0.1  | v    |
|   | V <sub>OL</sub> | $V_{\text{IN}} = V_{\text{IL}}$ |                          | 4.5                   | —    | 0.0                   | 0.1                   |                       | 0.1  |      |
|   |                 |                                 | $I_{OL} = 4 \text{ mA}$  | 3.0                   | —    |                       | 0.36                  |                       | 0.44 |      |
|   |                 |                                 | $I_{OL} = 8 \text{ mA}$  | 4.5                   | —    |                       | 0.36                  |                       | 0.44 |      |
| Input leakage current                                       | I <sub>IN</sub> | V <sub>IN</sub> = 5.5 V or GND  |                          | 0~5.5                 |      | _                     | ±0.1                  | _                     | ±1.0 | μA   |
| Quiescent supply current                                    | ICC             | $V_{IN} = V_{CC}$               | or GND                   | 5.5                   | _    | _                     | 2.0                   | _                     | 20.0 | μΑ   |

### AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

| Characteristics               | Symbol          | Test Condition   |                     | Ta = 25°C            |     |      | Ta = -40~85°C |      | Unit |       |
|-------------------------------|-----------------|--|---------------------|----------------------|-----|------|---------------|------|------|-------|
|                               |                 |  | V <sub>CC</sub> (V) | C <sub>L (</sub> pF) | Min | Тур. | Max           | Min  | Max  | Unit  |
| Propagation delay time        | tplh<br>tphl    | $\begin{array}{c} 3.3\pm0.3\\\\ \hline\\ 5.0\pm0.5\end{array}$ | 33+03               | 15                   |     | 5.0  | 7.1           | 1.0  | 8.5  |       |
|                               |                 |  | 50                  |                      | 7.5 | 10.6 | 1.0           | 12.0 | ns   |       |
|                               |                 |  | $5.0\pm0.5$         | 15                   | _   | 3.8  | 5.5           | 1.0  | 6.5  | - 113 |
|                               |                 |  |                     | 50                   |     | 5.3  | 7.5           | 1.0  | 8.5  |       |
| Input capacitance             | C <sub>IN</sub> |  | _                   |                      | _   | 4    | 10            |      | 10   | pF    |
| Power dissipation capacitance | C <sub>PD</sub> |  | (Note)              |                      |     | 15   |               |      | _    | pF    |

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

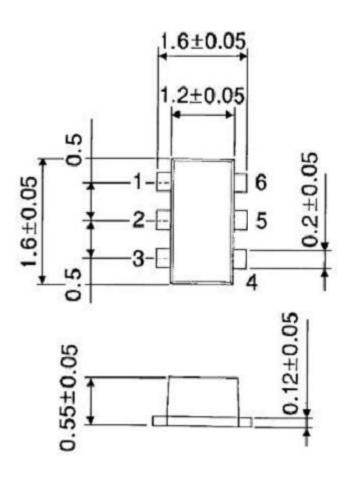
Average operating current can be obtained by the equation:

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2$ 

### Package Dimensions

SON6-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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